

International Rectifier

HEXFET® POWER MOSFET

Provisional Data Sheet No. PD-9.428B

JANTX2N6792
JANTXV2N6792
[REF:MIL-PRF-19500/555]
[GENERIC:IRFF320]
N-CHANNEL

400 Volt, 1.8Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

Part Number	BVDSS	RDS(on)	ID
JANTX2N6792	400V	1.8Ω	2.0A
JANTXV2N6792			

Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed

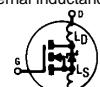
Absolute Maximum Ratings

	Parameter	JANTX2N6792, JANTXV2N6792	Units
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	2.0	A
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	1.25	
IDM	Pulsed Drain Current ①	8.0	W
PD @ TC = 25°C	Max. Power Dissipation	20	
	Linear Derating Factor	0.16	W/K ⑤
VGS	Gate-to-Source Voltage	±20	V
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns
TJ TSTG	Operating Junction Storage Temperature Range	-55 to 150	°C g
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10.5 seconds)	
	Weight	0.98 (typical)	

JANTX2N6792, JANTXV2N6792 Device

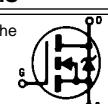
Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain-to-Source Breakdown Voltage	400	—	—	V	$V_{GS} = 0\text{V}, I_D = 1.0\text{ mA}$
$\Delta BVDSS/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	—	0.37	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $I_D = 1.0\text{ mA}$
RDS(on)	Static Drain-to-Source On-State Resistance	—	—	1.8	Ω	$V_{GS} = 10\text{V}, I_D = 1.25\text{A}$ ^④
		—	—	2.0		$V_{GS} = 10\text{V}, I_D = 2.0\text{A}$
VGS(th)	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
gfs	Forward Transconductance	1.0	—	—	S (mS)	$V_{DS} > 15\text{V}, I_{DS} = 1.25\text{A}$ ^④
IDSS	Zero Gate Voltage Drain Current	—	—	25	μA	$V_{DS} = 0.8 \times \text{Max Rating}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 0.8 \times \text{Max Rating}$ $V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
IGSS	Gate-to-Source Leakage Forward	—	—	100	nA	$V_{GS} = 20\text{V}$
IGSS	Gate-to-Source Leakage Reverse	—	—	-100		$V_{GS} = -20\text{V}$
Qg	Total Gate Charge	8.7	—	15.5	nC	$V_{GS} = 10\text{V}, I_D = 2.0\text{A}$
Qgs	Gate-to-Source Charge	0.8	—	2.6		$V_{DS} = \text{Max. Rating} \times 0.5$ see figures 6 and 13
Qgd	Gate-to-Drain ("Miller") Charge	4.2	—	8.3	ns	$V_{DD} = 200\text{V}, I_D = 2.0\text{A},$ $R_G = 7.5\Omega, V_{GS} = 10\text{V}$ see figure 10
td(on)	Turn-On Delay Time	—	—	40		
tr	Rise Time	—	—	35		
td(off)	Turn-Off Delay Time	—	—	60		
tf	Fall Time	—	—	35		
LD	Internal Drain Inductance	—	5.0	—	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
LS	Internal Source Inductance	—	15	—		Measured from the source lead, 6mm (0.25 in.) from package bonding pad to source bonding pad.
Ciss	Input Capacitance	—	350	—	pF	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}$ $f = 1.0\text{ MHz}$ see figure 5
Coss	Output Capacitance	—	100	—		
Crss	Reverse Transfer Capacitance	—	45	—		



Source-Drain Diode Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current (Body Diode)	—	—	2.0	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier.
ISM	Pulse Source Current (Body Diode) ^①	—	—	8.0		
VSD	Diode Forward Voltage	—	—	1.4	V	$T_j = 25^\circ\text{C}, I_S = 2.0\text{A}, V_{GS} = 0\text{V}$ ^④
t _{rr}	Reverse Recovery Time	—	—	650	ns	$T_j = 25^\circ\text{C}, I_F = 2.0\text{A}, dI/dt \leq 100\text{A}/\mu\text{s}$
QRR	Reverse Recovery Charge	—	—	5.0	μC	$V_{DD} \leq 50\text{V}$ ^④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.				



Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R _{thJC}	Junction-to-Case	—	—	6.25	K/W	Typical socket mount
	Junction-to-Ambient	—	—	175		

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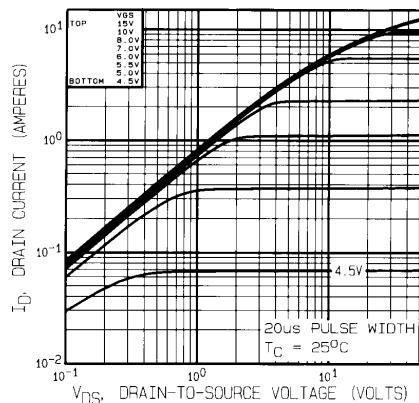


Fig. 1 — Typical Output Characteristics
 $T_C = 25^\circ\text{C}$

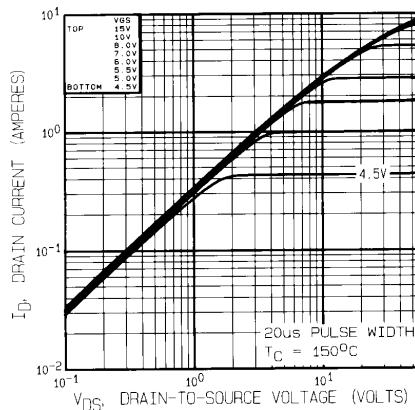


Fig. 2 — Typical Output Characteristics
 $T_C = 150^\circ\text{C}$

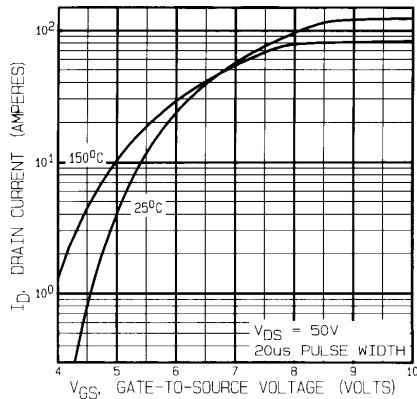


Fig. 3 — Typical Transfer Characteristics

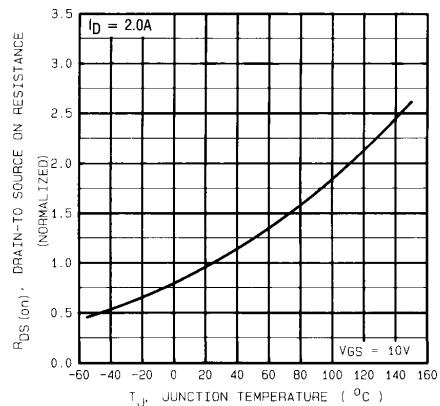


Fig. 4 — Normalized On-Resistance Vs. Temperature

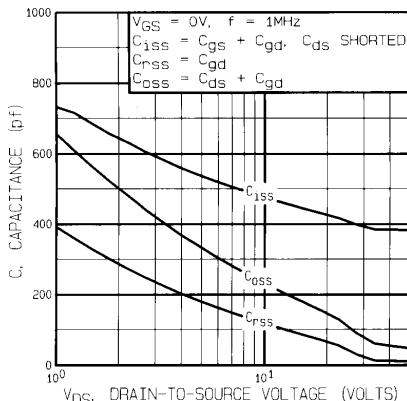


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

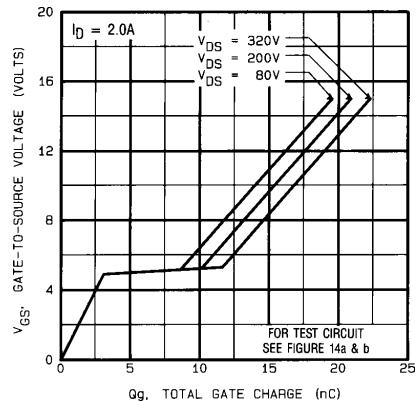


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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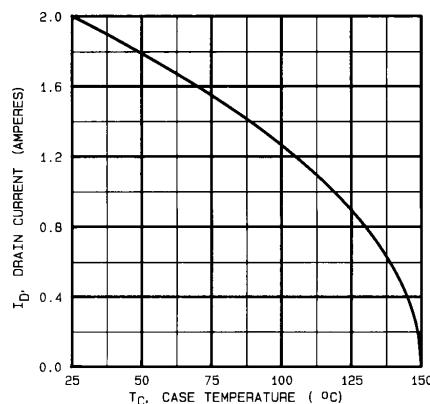
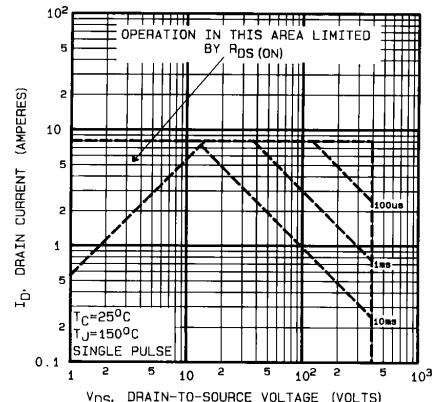
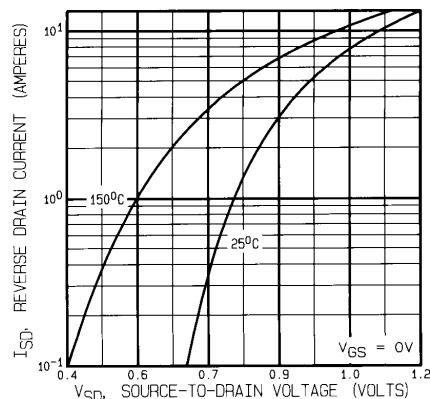


Fig. 9 — Maximum Drain Current Vs. Case Temperature

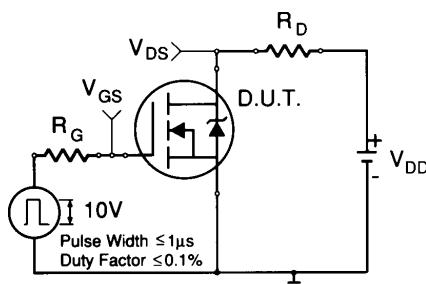


Fig. 10a — Switching Time Test Circuit

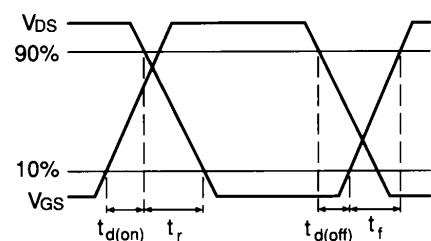


Fig. 10b — Switching Time Waveforms

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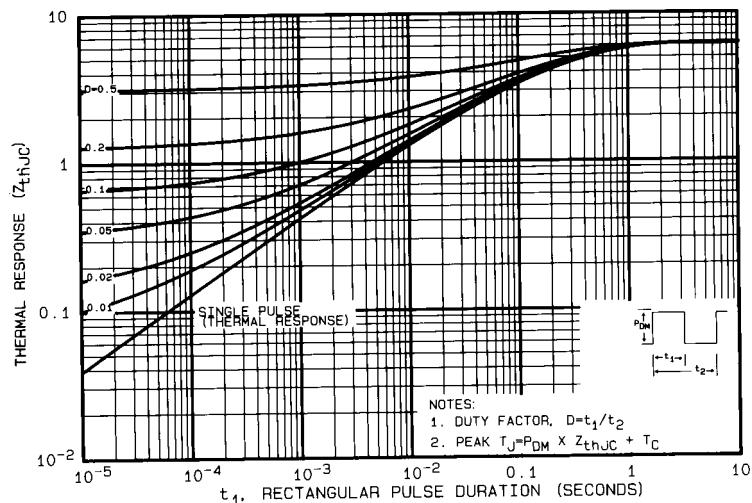


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

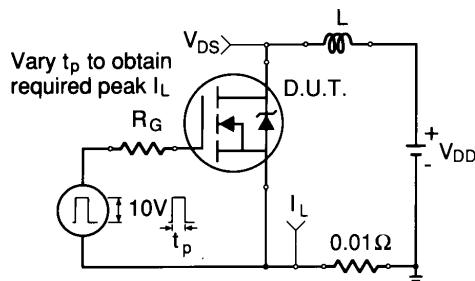


Fig. 12a — Unclamped Inductive Test Circuit

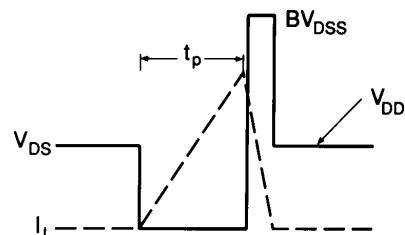


Fig. 12b — Unclamped Inductive Waveforms

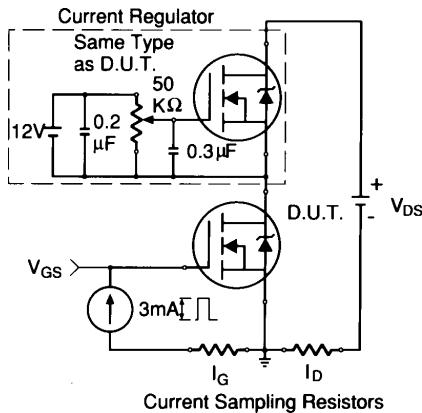


Fig. 13a — Gate Charge Test Circuit

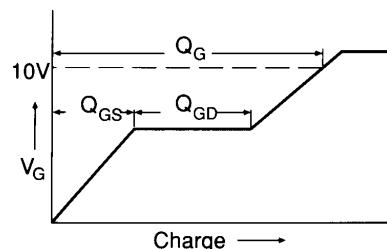
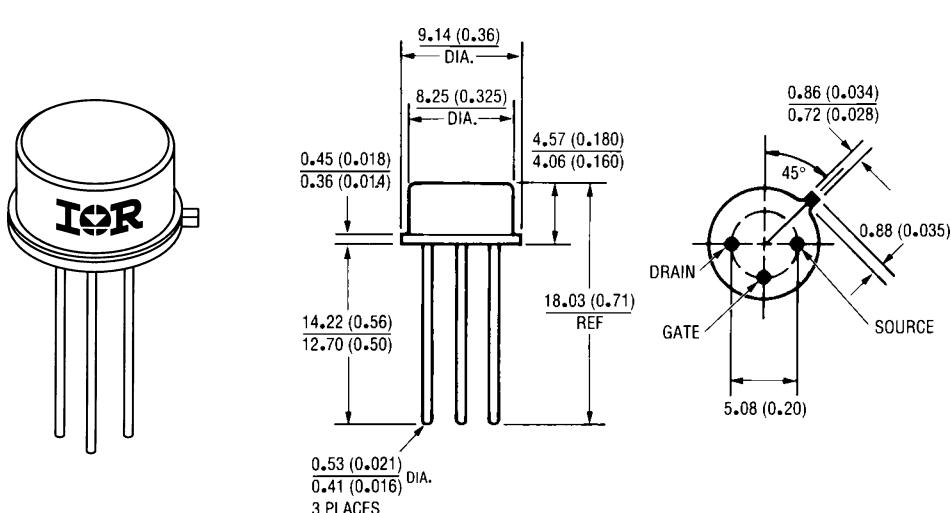


Fig. 13b — Basic Gate Charge Waveform

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- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
(see figure 11)
- ② @ $V_{DD} = 50V$, Starting $T_J = 25^\circ C$,
 $EAS = [0.5 * L * (I_L^2) * [BV_{DSS}/(BV_{DSS}-V_{DD})]]$
 Peak $I_L = 2.0A$, $V_{GS} = 10V$, $25 \leq R_G \leq 200\Omega$
- ③ $I_{SD} \leq 2.0A$, $dI/dt \leq 65A/\mu s$,
 $V_{DD} \leq BV_{DSS}$, $T_J \leq 150^\circ C$
- ④ Pulse width $\leq 300 \mu s$; Duty Cycle $\leq 2\%$
- ⑤ $K/W = ^\circ C/W$
 $W/K = W/^{\circ}C$

Case Outline and Dimensions — TO-205AF (Modified TO-39)



All dimensions are shown millimeters (inches)

International
IR Rectifier

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